

## **Quarterly Reliability Monitoring Results**

## Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number PZU30BA-Q Part Description										
									Nexperia DHAM			
									SMD package			
		Test Conditions	Duration	# Lots	# Quantity	# Rejects						
			TEST									
			Pre- and Post-Stress									
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below						
		JESD22-A113										
		Bake Tamb = 125 °C	24 hours									
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours									
# A1	Preconditioning	Reflow soldering	3 cycles	1168	66640	0						
		MIL-STD-750-1										
	HTRB	M1038 Method A										
	,	Tj = Tjmax, VR = 80 % of rated reverse										
# B1	Bias	voltage	1000 hours	198	11960	0						
		MIL-STD-750-1										
		M1038 Method B										
" D41	SSOP	Tj = Tjmax, Iz = 100% of max. datasheet	10001	2.4	1760							
# B1b	Steady State Operational	reverse current	1000 hours	24	1760	0						
	T-0	JECD22 A104										
# 0.4	TC Temperature Cycling	JESD22-A104 -65 °C to Timax, not to exceed 150°C	1000 eveles	240	14000	0						
# A4	remperature cycling	-03 C to Tjillax, flot to exceed 130 C	1000 cycles	240	14800	0						
	UHAST	JESD22-A118										
# A3 <b>or</b>	Unbiased HAST	Tamb = 130 °C, RH = 85 %										
" 7.5 <b>G.</b>	Olibiasea linio l		-96 hours	240	14800	0						
	AC	JESD22-A102 Tamb = 121 °C, RH = 100 %										
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)										
" AJ dic												
	H3TRB	JESD22-A101										
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of										
# A2 alt	Temperature Reverse Bias		1000 hours	240	14800	0						
	,	MIL-STD-750 Method 1037				-						
	IOL	ton = toff, devices powered to insure $\Delta T_j$ =										
# A5	Intermittent Operating Life	, .	1000 hours	264	16720	0						
	. 5											
	RSH	JESD22-A111										
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	184	5520	0						
	SD											
# C10	Solderability	J-STD-002		501	5010	0						

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Zener	11960	0	0,36	2,82E+09

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